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## Low-energy electron microscopy on two-dimensional systems : growth, potentiometry and band structure mapping

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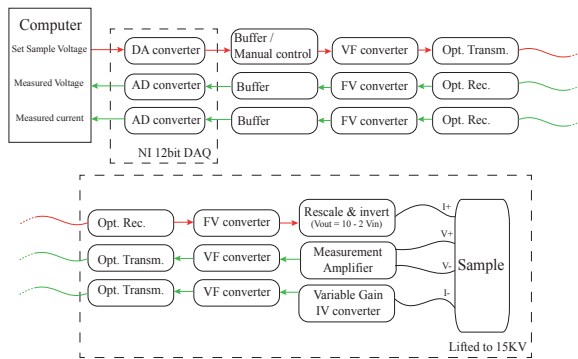
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# A

## Electronic circuits

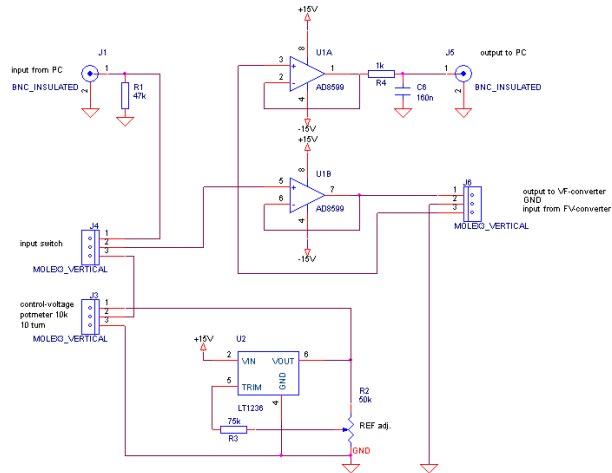
In this appendix the electronic circuits used for potentiometry measurements can be found.



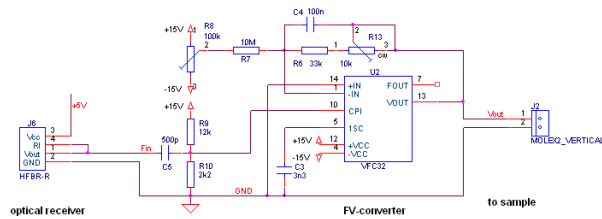
**Fig. A.1:** Diagram showing how signals travel from the computer to the sample and back. Electronic diagrams for the individual components can be found in the subsequent figures.

## A. ELECTRONIC CIRCUITS

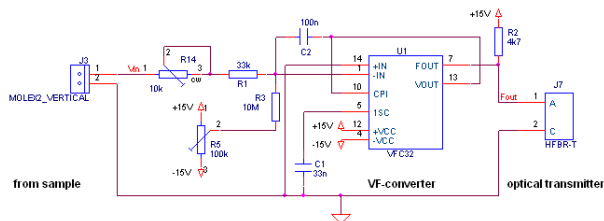
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**Fig. A.2:** Electronic diagram for the buffer and the manual control



**Fig. A.3:** Electronic diagram for the frequency to voltage converter



**Fig. A.4:** Electronic diagram for the voltage to frequency converter

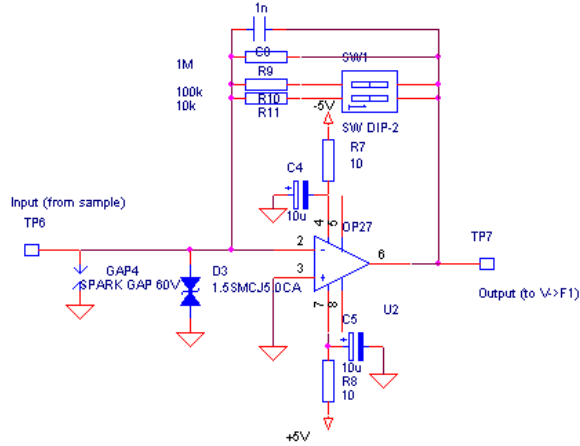


Fig. A.5: Electronic diagram for the iv-converter

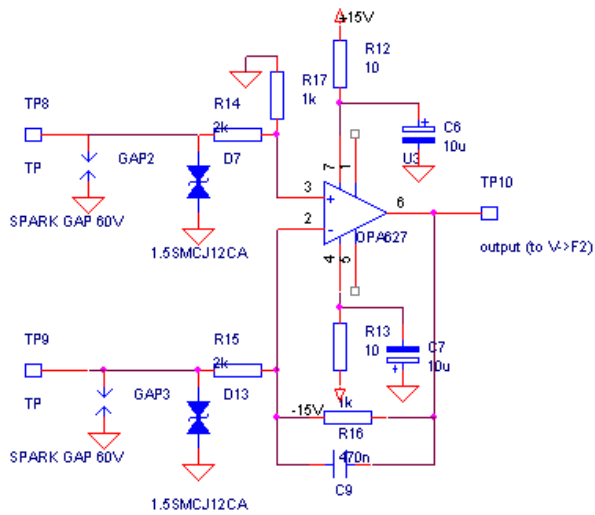
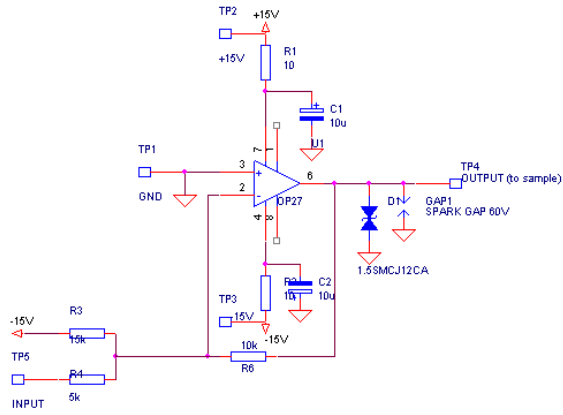


Fig. A.6: Electronic diagram for the measurement amplifier



**Fig. A.7:** Electronic diagram for the rescaling of the 0-10 V signal of the FV-converter to a -10-10V signal.